Se	arcn Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/673,440	LEE ET AL.	
Examiner	Art Unit	
Shean C. Wu	1756	

SEARCHED			
Class	Subclass	Date	Examiner
252	299.61	7/12/2005	sw
	299.62		
	299.63		
	299.66		
	299.67		
560	79		
	127		
546	126		
	135		
	,		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
252	299.61	7/12/2005	sw
	299.62		
	299.63		
	6, 299.67; 5;560/79,127		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
CAS on line text search, see attachment	7/12/2005	sw
West update, see attachment		
inventors search, see attachment		